

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/066,188	TEIG ET AL.
	Examiner	Art Unit
	Sun J. Lin	2825

**SEARCHED**

Class	Subclass	Date	Examiner
716	12	12/30/2005	JSL
716	7	12/30/2005	JSL
716	9	12/30/2005	JSL
716	10	12/30/2005	JSL
716	11	12/30/2005	JSL
716	13	12/30/2005	JSL
716	14	12/30/2005	JSL
716	18	12/30/2005	JSL
716	3	12/30/2005	JSL

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
716	3,7,9	12/30/2005	JSL
716	10-14	12/30/2005	JSL
716	18	12/30/2005	JSL